0		2000/09/21 19:44	USPAT	10 and (substrate with oxidiz\$3)	330	L11	BRS	8
0		2000/09/21 16:57	USPAT	8 and (implant\$3 dop\$4)	647	L10	BRS	7
0		2000/09/21 16:55	USPAT	<u>U</u> <u>W</u>	ω	L9	BRS	6
0		2000/09/21 16:53	USPAT	7 and (oxidiz\$3)	761	Ь8	BRS	5
0		)9/	USPAT	4 5	1670	L7	BRS	4
0		2000/09/21 16:48	USPAT	3 and join\$3	525	L5	BRS	ω
0		2000/09/21 16:47	USPAT	3 and bond\$3	1418	L4	BRS	2
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and (dielectric insulat\$3 oxide)) and (dielectric insulat\$3 oxide)) and (amorphous adj silicon)) (((substrate semiconductor wafer) and (dielectric insulat\$3 oxide)) and (mono adj crystal\$3 adj silicon)) (((substrate semiconductor wafer) and (dielectric insulat\$3 oxide)) and (single adj crystal\$6 adj silicon)) (((substrate semiconductor wafer) and (dielectric insulat\$3 oxide)) and polysilicon)) and implant\$3 oxide)) and polysilicon)) and implant\$3) and ((non adj dopant)	Search Text
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0	 14:18	2000/09/14	USPAT	<pre>((((((substrate semiconductor wafer)     and (dielectric insulat\$3 oxide)) and     (amorphous adj silicon)) (((substrate     semiconductor wafer) and (dielectric     insulat\$3 oxide)) and (mono adj     crystal\$3 adj silicon)) (((substrate     semiconductor wafer) and (dielectric     insulat\$3 oxide)) and (single adj     crystal\$6 adj silicon)) (((substrate     semiconductor wafer) and (dielectric     insulat\$3 oxide)) and polysilicon))     and implant\$3) and (nitrogen)</pre>	3248	BRS	12
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